

<b>Search Notes</b> 	<b>Application/Control No.</b>  10/768,416	<b>Applicant(s)/Patent under Reexamination</b>  SHENKAR ET AL.
	<b>Examiner</b>  David T. Fidei	<b>Art Unit</b>  3728

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner